

The Semiconductor Wafer Test Conference

DATE: Wednesday, November 19, 2025
LOCATION: Ch \pm M-ku, Fukuoka-ken, JP

Event Description

The Semiconductor Wafer Test Conference is a premier expos event in Ch \pm M-ku. This event attracts visitors from around the world and significantly impacts local hotel demand, creating opportunities for strategic revenue management and guest experience optimization.

Key Information

Category: expos

Importance Rank: 45/100

Expected Attendance: 550 people

Event ID: 7NoyzWdDima5UE86Yh

Hotel Demand Indicators

ADR Impact Index: 5.3x baseline (varies by property tier & location)

Occupancy Impact: +60 percentage points over baseline

Booking Lead Time: Demand begins 30 days before event

Impact Radius: 15km from venue

Estimated Room Nights: 220 across all properties

Note: Actual impact varies by property location, star rating, and local market conditions.